

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10591824	CHAN ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
SUCHIRA PANDE	1637	

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Google search	June 2009	SP
PALM Inventor name search	July 2009	SP
East Search	July 2009	SP
Pubmed search	July 2009	SP
SPEs Gary Benzion, Peter Paras and Chris Low were consulted re "subject of chinese decent" phrase in claims. Use of this phrase makes this a SAWs case. It was decided that 112 2nd should be done as we do not know how much chinese does one have to be to qualify and how to determine that requisite percentage?	July 2009	SP
Updated	February 2010	DCT

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
	Claim search performed	2/3/2010	DCT